

A9-CKD-01

Product Brief



DDR5 Clock Driver Test Card

A versatile DIMM test card focused on Clock Driver Signal Integrity (SI) measurement. It Minimizes signal integrity impact by using JEDEC reference load termination in combination with minimal trace lengths. Provides high impedance oscilloscope probing access to Tx and Rx outputs of the Clock Driver under test. Clock Driver SI test card are compatible with Astek's A9-CTC2.

Features

- Clock Driver test points compatible with Keysight MX0100 high performance oscilloscope probes
- Minimizes SI impact using JEDEC reference load termination.

Test Measurements

- Jitter
- t_{STAOFF}/t_{DYNOFF}
- Ron
- Slew Rate
- Vox

Configuration

- All critical passive Rs and Cs installed
- Clock Drivers provided by customer

Ordering Information

Model Number	Product Description
A9-CKD-01	DDR5 Clock Driver Test Card

For more information, contact your Keysight sales representative or visit the Astek web site at:
www.astekcorp.com